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CERTIFICATE OF MAILING
37 C.F.R. § 1.8

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March 2, 2005
Date

Mary Paul
Signature

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

ELFIDO COSS, JR.
PATRICK M. COWAN
RICHARD J. MARKLE
TOM TSE

Group Art Unit: 2812

Examiner: Unknown

Atty. Dkt. No.: 2000.088500/TT4616

Customer No.: 23720

Serial No.: 10/700,175

Filed: November 3, 2003

For: FAULT DETECTION AND CONTROL
METHODOLOGIES FOR ION
IMPLANTATION PROCESSES, AND
SYSTEM FOR PERFORMING SAME

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed documents required by 37 C.F.R. § 1.98(a)(2) are enclosed for the convenience of the Examiner.

In accordance with 37 C.F.R. §§ 1.97(g),(h), this Supplemental Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b).

In accordance with 37 C.F.R. § 1.97(e)(1), Applicants hereby certify that each item of information contained in this Supplemental Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the present statement, as evidenced by the date of the enclosed PCT Search Report.

Applicants respectfully request that the listed documents be made of record in the present case.

Respectfully submitted,

WILLIAMS, MORGAN & AMERSON
CUSTOMER NUMBER: 23720

A handwritten signature in black ink, appearing to read 'J. Mike Amerson', is written over a horizontal line.

Date: March 2, 2005

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Form PTO-1449 (modified)

Atty. Docket No.
2000.088500/TT4616Serial No.
10/700,175

List of Patents and Publications for Applicant's

Applicant

Elfido Coss, Jr., Patrick M. Cowan, Richard J. Markle
and Tom Tse

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Filing Date:
November 3, 2003Group:
2812U.S. Patent Documents
*See Page 1*Foreign Patent Documents
*See Page 1*Other Art
See Page 1

U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A2	6,055,460	4/25/00	Shopbell	700	121	
	A3	2002/0055801 A1	5/09/02	Reiss <i>et al.</i>	700	111	
	A4	2003/0042427 A1	3/06/03	Sullivan <i>et al.</i>	250	397	
	A5						
	A6						

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						
	B2						
	B3						

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	PCT Search Report from PCT/US2004/017617, dated 12/02/04
	C2	Rendon <i>et al.</i> , "Ion Implant Data Log Analysis for Process Control and Fault Detection," <i>IEEE</i> , pp. 331-334, 2002
	C3	

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.